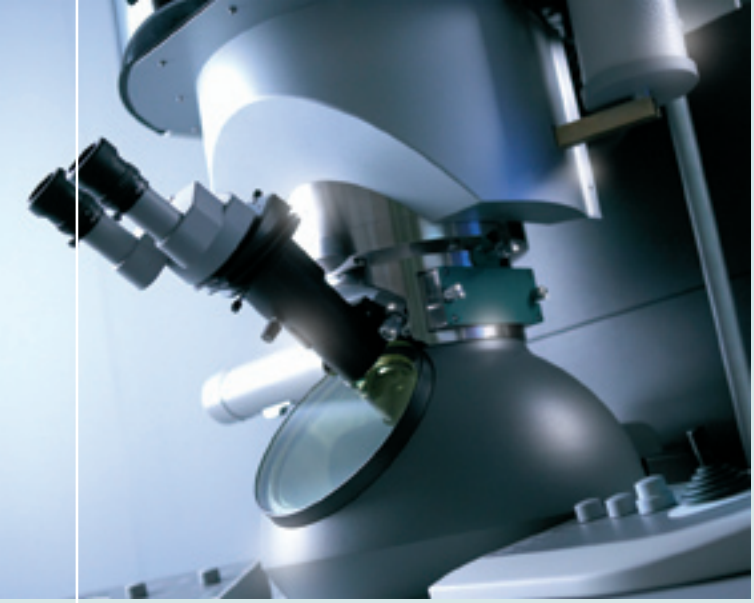
FEI COMPANY™
TOOLS FOR NANOTECH

Titan™ 80-300

Expanding the Boundaries and Achieving New Results



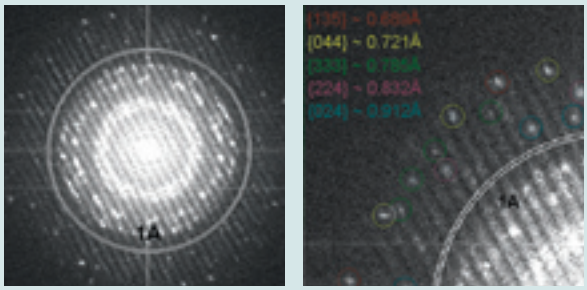
Sub-Ångström Era

Nanoresearch strives to increase our understanding of nanostructures and functional materials by linking the macroscopic material properties to the properties at the smallest level of detail: down to the atoms. This continuing drive pushes for the better understanding of local atom organization and for the characterization of atoms, chemical bonding and even the electronic structure.

The recognized and ever growing need to truly image and analyze nanostructures with the highest level of detail implies setting a new standard for achieving new results in the field of nanoresearch microscopy. Sub-Ångström aberration-corrected analytical microscopy is the benchmark and presents a new set of rules in this new era. A classical electron microscope's fundamental spherical aberration can be corrected and the typical C_s constant is of less importance: the point resolution now equals the information limit. The information limit is governed by the stability of the microscope and is the best measure for corrected microscopy quality and performance. The requirement for unsurpassed stability calls for a corrected microscope design that complies with the stringent needs for maximum mechanical, electronic and thermal stability, as well as precision alignment of the advanced components.

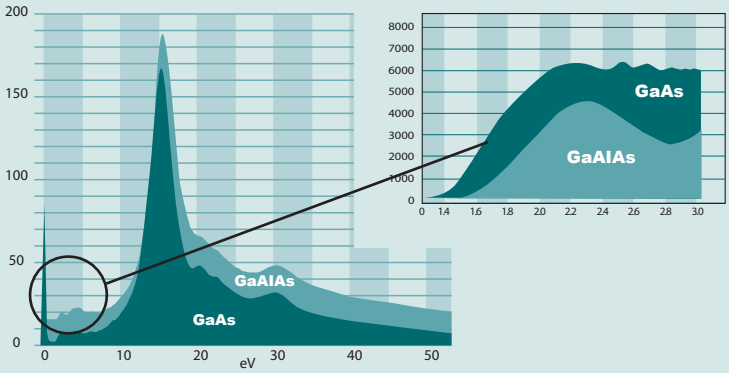
The Titan 80-300™ microscope incorporates a newly designed platform dedicated to the principles of ultimate stability, ultimate performance and ultimate flexibility for corrector and monochromator technology and its applications. The microscope transfers information deep into sub-Ångström resolution making way for the highest performance available in both TEM and STEM. Titan obtains lateral resolution far better than 1 Ångström (see figure below) and energy resolution down to 0.1 eV. This presents new information of the electronic properties of materials such as bonding states or band gaps with unprecedented spatial resolution. An innovative and modular patent pending design makes a field-upgrade of C_s correctors possible. Thus, allowing you a step by step approach to corrected microscopy in your laboratory.

The stability, performance and ease-of-use of Titan enables corrected microscopy to be taken to the next level where new discoveries on the structure-property relationships of materials become possible at ever-decreasing scales. Titan is poised to bring electron microscopy into a new era by expanding the boundaries and achieving new results in nanoresearch.

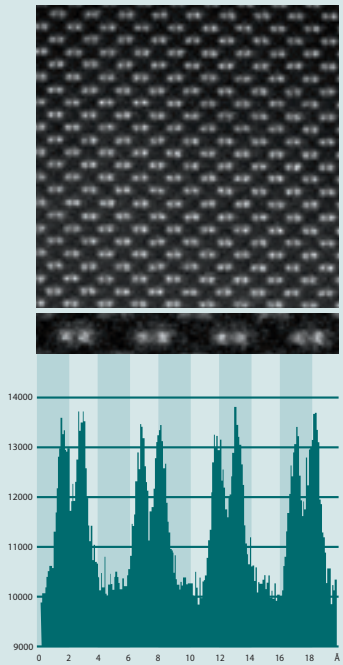


New Rules: Classical "C_s" is now irrelevant and point resolution now equals information limit. Information limit is all about stability. Titan's Information Limit: Young's Fringes of poly crystalline gold. Fringes extend well below 1.0 Å

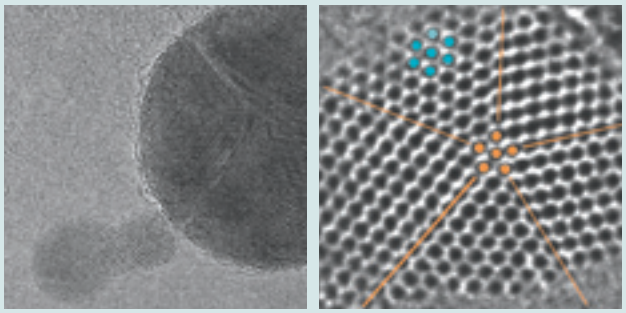
Ultimate Performance, Ultimate Stability, Ultimate Flexibility



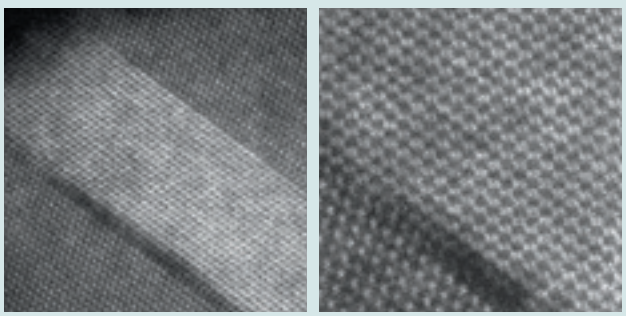
High-resolution EELS spectrum of GaAs and GaAlAs using Titan's monochromator technology. Uniquely, band gap thresholds can be measured as well as the energy shift due to the Al doping.



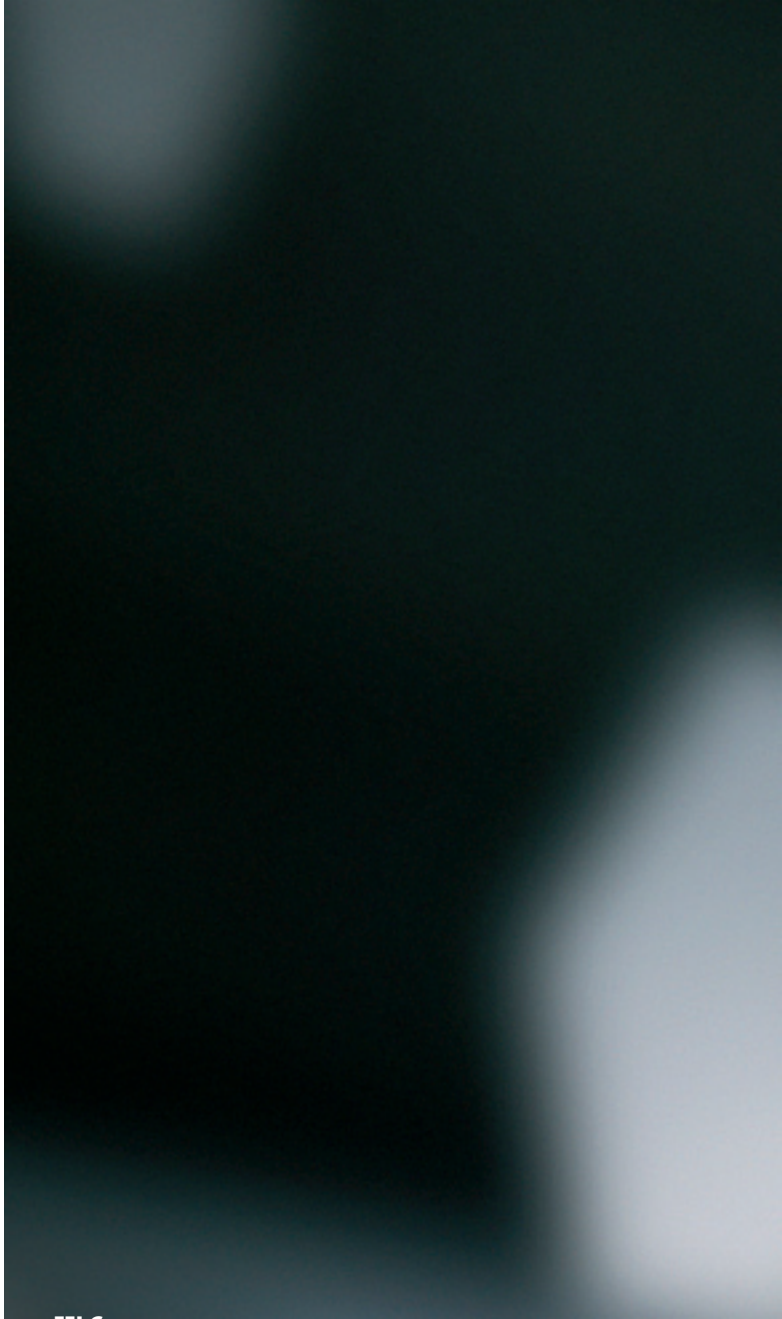
Atomic resolution HR-STEM image of Si <110> using Titan's C_S probe corrector. The intensity profile across the dumbbell structure is shown at the bottom. The atoms are clearly resolved.



Atomic resolution HR-TEM direct image of gold nano particles using Titan's C_S image corrector. Individual atom columns can be clearly resolved and 5-fold coordination of twin boundaries in gold is apparent.



Atomic resolution HR-STEM image of diamond <110> using Titan's C_S probe corrector. Diamond dumbbells are shown at a spacing of 0.9Å. The twin and grain boundaries can be clearly imaged.



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